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Addendum

Addendum: Fang, Q.; Maldague, X. A Method of Defect Depth Estimation for Simulated Infrared Thermography Data with Deep Learning. *Appl. Sci.* 2020, *10*, 6819

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The authors wish to make the following corrections to this paper: [1].

The original version of our article (Fang, Q.; Maldague, X. A Method of Defect Depth Estimation for Simulated Infrared Thermography Data with Deep Learning. 2020, 10, 6819) did not include the complete funding and acknowledgements. The authors wish to change the information in the Funding section and Acknowledgements section from:

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The authors apologize for any inconvenience caused. The authors state also that the scientific conclusions are unaffected.

Reference

1. Fang, Q.; Maldague, X. A Method of Defect Depth Estimation for Simulated Infrared Thermography Data with Deep Learning. *Appl. Sci.* **2020**, *10*, 6819. [CrossRef]

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